PCT

PATENT

Docket No.: 4752-005



In re Application of

Inventor(s): Naofumi AOKI et al.

Confirmation No. 1411

U.S. Patent Application No. 10/531,584

Filed: April 18, 2005

For: UNAUTHORIZED-ALTERATION DETECTING METHOD, UNAUTHORIZED-

ALTERATION DETECTING PROGRAM, AND RECORDING MEDIUM HAVING

RECORDED THE PROGRAM

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

This is further to the Information Disclosure Statement as filed on April 18, 2005. In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required.

Respectfully submitted,

LOWE HAUPTMAN & BERNER, LLP

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Date: November 22, 2005

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INFORMATION DISCLOSURE CITATION IN AN

ATTY. DOCKET NO. 4752-005

U.S. PATENT APPLICATION NO.

10/531,584

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APPLICATION (PTO-1449)				Naofumi AOKI et al.					
				FILING DATE April 18, 2005					
		U.S. PA	FENT DOCUMENTS						
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EXAMINER			DATE CONSIDER						

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.